

## 2-Channel Voltage Detectors

### ■ GENERAL DESCRIPTION

The XC612 series consist of 2 voltage detectors, in 1 mini-molded, SOT-25 package.

The series provides accuracy and low power consumption through CMOS processing and laser trimming and consists of a highly accurate voltage reference source, 2 comparators, hysteresis and output driver circuits.

The input ( $V_{IN1}$ ) for voltage detector 1 ( $V_{D1}$ ) dually functions as the power supply pin for both detector 1 ( $V_{D1}$ ) and detector 2 ( $V_{D2}$ ).

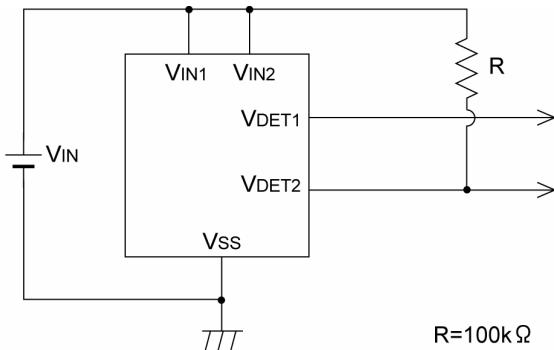
### ■ APPLICATIONS

- Microprocessor reset circuitry
- Memory battery back-up circuits
- Power-on reset circuits
- Power failure detection
- System battery life and charge voltage monitors
- Delay circuitry

### ■ FEATURES

- |                                     |  |
|-------------------------------------|--|
| <b>Highly Accurate</b>              | : Setting voltage accuracy $\pm 2\%$   |
| <b>Low Power Consumption</b>        | : $2.0 \mu A$ (TYP.)<br>( $V_{IN1}=V_{IN2}=2.0V$ , Static state)   |
| <b>Detect Voltage</b>               | : $1.5V \sim 5.0V$ programmable in<br>100mV steps. Detector's voltages can<br>be set-up independently<br>Conditionally;<br>$XC612N : V_{DET1} > V_{DET2}$<br>$XC612D, XC612E : V_{DET1} \geq V_{DET2},$<br>$V_{DET1} < V_{DET2}$ |
| <b>Operating Voltage Range</b>      | : $1.5V \sim 10.0V$  |
| <b>Temperature Characteristics</b>  | : $\pm 100ppm/{^\circ}C$ (TYP.)  |
| <b>Output Configuration</b>         | : N-channel open drain   |
| <b>CMOS Low Power Consumption</b>   |  |
| <b>2 Voltage Detectors Built-in</b> |  |
| <b>Small Package</b>                | : SOT-25 (150mW) mini-mold   |
- \* CMOS Output is under development

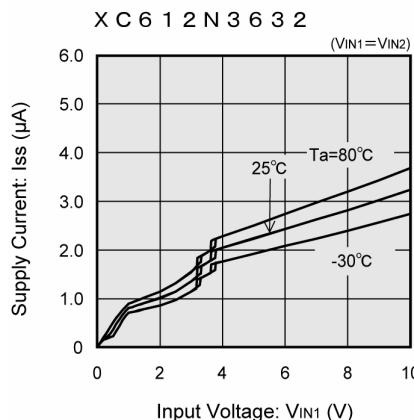
### ■ TYPICAL APPLICATION CRICUIT



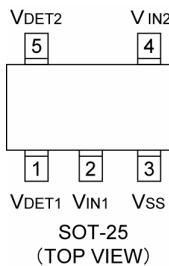
$V_{DET1}$  : CMOS,  $V_{DET2}$  : N-ch Open drain

### ■ TYPICAL PERFORMANCE CHARACTERISTICS

Supply Current vs. Input Voltae



## ■ PIN CONFIGURATION



## ■ PIN ASSIGNMENT

PIN NUMBER	PIN NAME	FUNCTION
1	VDET1	Voltage Detector 1 Output
2	VIN1	Detector 1 Input, Power Supply
3	Vss	Ground
4	VIN2	Voltage Detector 2 Input
5	VDET2	Voltage Detector 2 Output

## ■ PRODUCT CLASSIFICATION

### ● Selection Guide

TYPE	VDET1	VDET2
XC612N	N-ch Open Drain	N-ch Open Drain
XC612D	N-ch Open Drain	CMOS
XC612E	CMOS	N-ch Open Drain

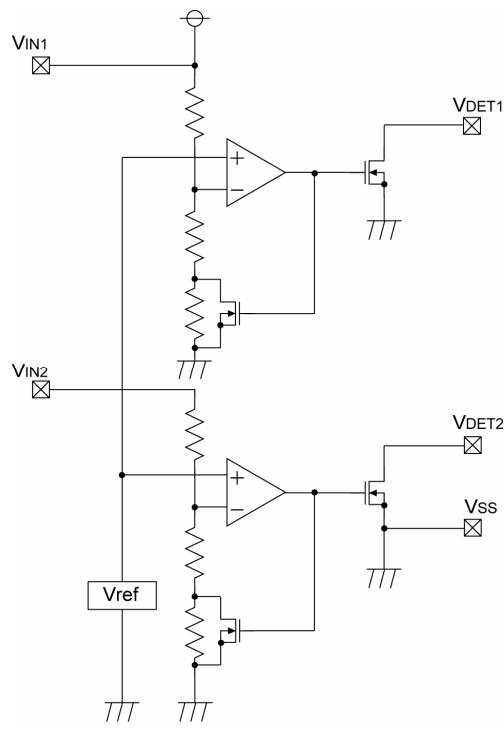
### ● Ordering Information

XC612①②③④⑤⑥⑦

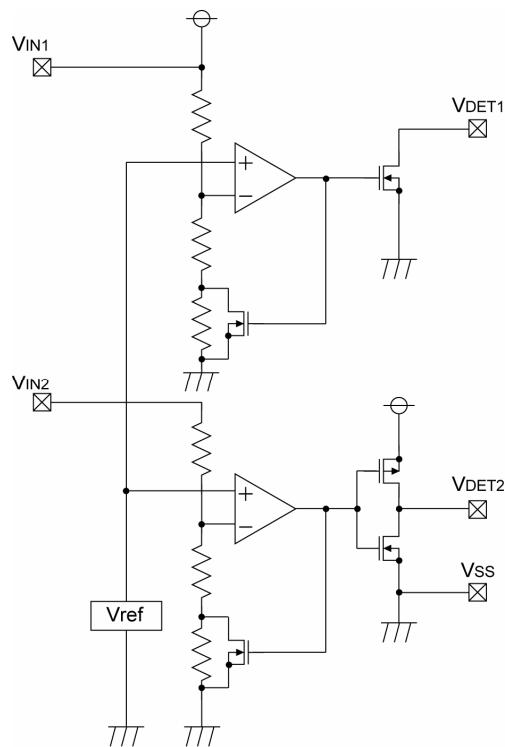
DESIGNATOR	DESCRIPTION	SYMBOL	DESCRIPTION
①	Output Configuration	N	: VDET1/VDET2: N-ch open drain
		D	: VDET1: N-ch open drain, VDET2: CMOS
		E	: VDET1: CMOS, VDET2: N-ch open drain
②③	Detect Voltage 1 (VDET1)	15~50	: VDET1: 2.5V→②25
④⑤	Detect Voltage 2 (VDET2)	15~50	: VDET2: 3.3V→③33
⑥	Package	M	: SOT-25 (SOT-23-5)
⑦	Device Orientation	R	: Embossed tape, standard feed
		L	: Embossed tape, reverse feed

## ■ BLOCK DIAGRAMS

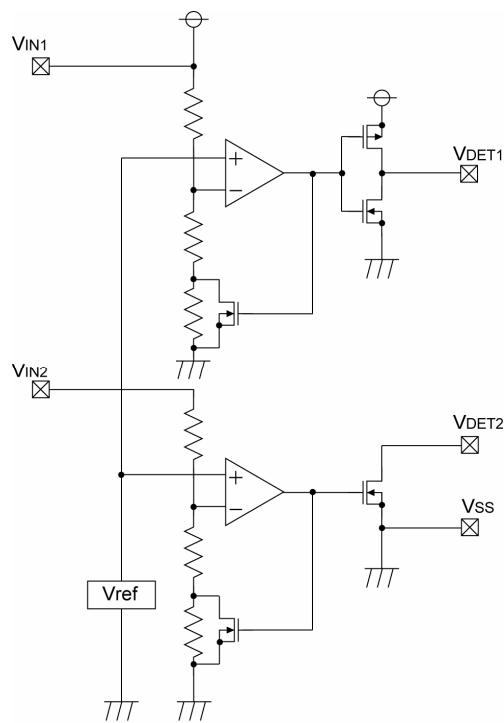
XC612N Series



XC612D Series



XC612E Series



## ■ ABSOLUTE MAXIMUM RATINGS

 $T_a = 25^\circ\text{C}$ 

PARAMETER		SYMBOL	RATINGS	UNITS
Input Voltage	V <sub>D</sub> 1	V <sub>IN1</sub>	12.0	V
	V <sub>D</sub> 2	V <sub>IN2</sub>	12.0	V
Output Voltage	V <sub>D</sub> 1 (N-ch open drain)	V <sub>VDET1</sub>	V <sub>SS</sub> – 0.3 ~ 12.0	V
	V <sub>D</sub> 1 (CMOS)		V <sub>SS</sub> – 0.3 ~ V <sub>IN1</sub> + 0.3	V
	V <sub>D</sub> 2 (N-ch open drain)	V <sub>VDET2</sub>	V <sub>SS</sub> – 0.3 ~ 12.0	V
	V <sub>D</sub> 2 (CMOS)		V <sub>SS</sub> – 0.3 ~ V <sub>IN1</sub> + 0.3	V
Output Current	V <sub>D</sub> 1	I <sub>VDET1</sub>	50	mA
	V <sub>D</sub> 2	I <sub>VDET2</sub>	50	mA
Power Dissipation		P <sub>d</sub>	150	mW
Operating Temperature Range		T <sub>opr</sub>	- 30 ~ + 80	°C
Storage Temperature Range		T <sub>stg</sub>	- 40 ~ + 125	°C

## ■ ELECTRICAL CHARACTERISTICS

Ta=25°C

PARAMETER	SYMBOL	CONDITIONS	MIN.	TYP.	MAX.	UNITS	CIRCUITS
Detect Voltage (VDET1) (*1)	VDF1	Voltage when VDET1 changes from H to L following a reduction of VIN1	VDF1 x 0.98	VDF1	VDF1 x 1.02	V	1
Detect Voltage (VDET2) (*1)	VDF2	Voltage when VDET2 changes from H to L following a reduction of VIN2	VDF2 x 0.98	VDF2	VDF2 x 1.02	V	1
Hysteresis Range 1	VHYS1	Voltage (VDR1) - VDF1 when VDET1 changes from L to H following an increase of VIN1	VDF1(T) x 0.02	VDF1(T) x 0.05	VDF1(T) x 0.08	V	1
Hysteresis Range 2	VHYS2	Voltage (VDR2) - VDF2 when VDET2 changes from L to H following an increase of VIN2	VDF2(T) x 0.02	VDF2(T) x 0.05	VDF2(T) x 0.08	V	1
Supply Current (VIN1 Input Current)	Iss	VIN1 = 1.5V VIN1 = 2.0V VIN1 = 3.0V VIN1 = 4.0V VIN1 = 5.0V	- - - - -	1.35 1.50 1.95 2.40 3.00	3.90 4.50 5.10 5.70 6.30	μ A	2
VIN2 Input Current	IIN2	VIN2 = 1.5V VIN2 = 2.0V VIN2 = 3.0V VIN2 = 4.0V VIN2 = 5.0V	- - - - -	0.45 0.50 0.65 0.80 1.00	1.30 1.50 1.70 1.90 2.10	μ A	2
Operating Voltage	VIN1	VDF(T) = 1.5V to 6.0V	1.0	-	10	V	—
Output Current (*3)	IVDET	VIN1 = 1.0V VIN1 = 2.0V N-ch, VDS=0.5V VIN1 = 3.0V VIN1 = 4.0V VIN1 = 5.0V P-ch (CMOS) VDS=-2.1V VIN1 = 8.0V	0.3 3.0 5.0 6.0 7.0 - -10.0	2.2 7.7 10.1 11.5 13.0 - -2.0	- - - - - - -	mA	3
Temperature Characteristics (*3)	$\frac{\Delta VDF}{\Delta Topr \cdot VDF}$	-30°C ≤ Topr ≤ 80°C	-	±100	-	ppm/°C	—
Delay Time (*3) (Release Voltage→ Output inversion)	tDLY	(VDR→VOUT inversion)	-	-	0.2	ms	5

## NOTE:

\*1 : VDF1(T), VDF2(T) : User specified detect voltage.

\*2 : Release voltage (VDR) = VDF + VHYS

\*3 : Those parameters marked with an asterisk apply to both VDET1 and VDET2.

\*4 : Input Voltage : please ensure that VIN1 &gt; VIN2

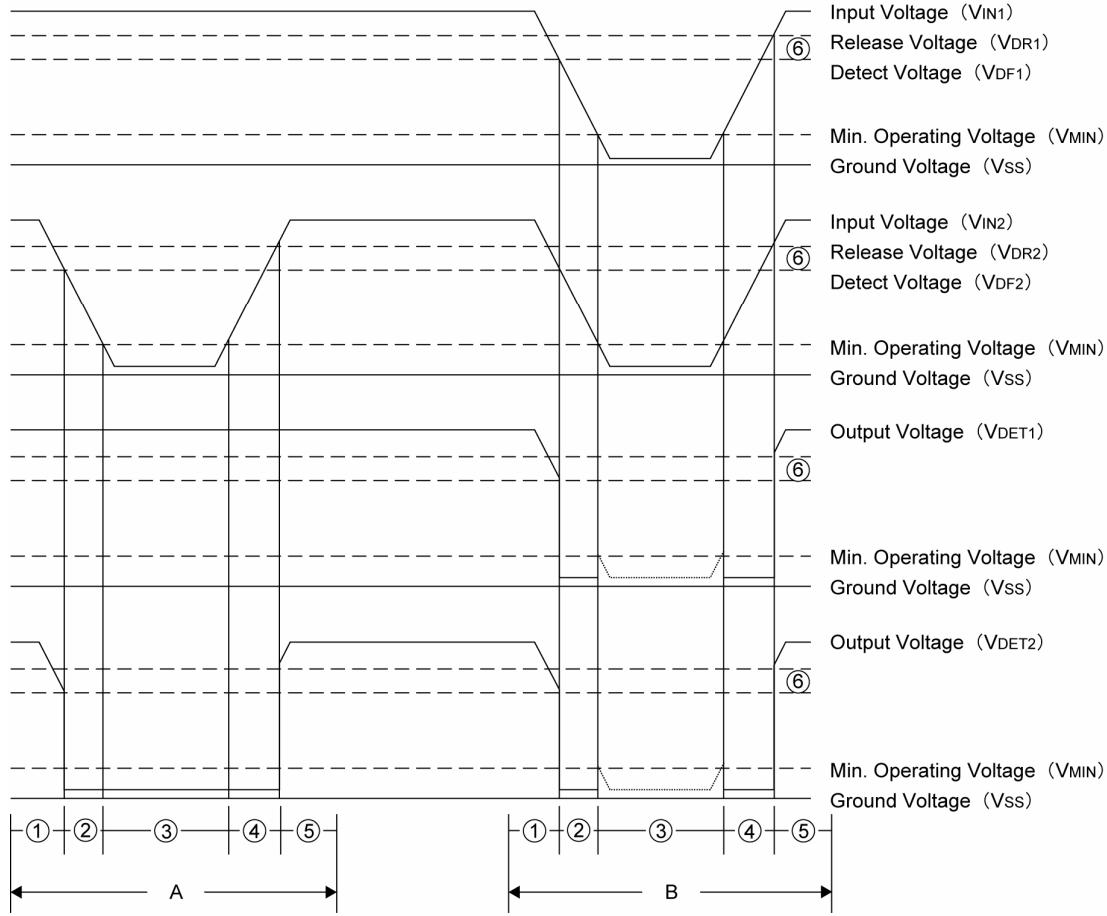
(Input voltage of XC612D and XC612E series : please ensure that VIN1 ≥ VIN2, VIN1 &lt; VIN2.)

\*5 : VIN1 pin serve both Iss and power supply pin so that VIN2 operates VIN1 as a power supply source. For normal operation of VIN2, operating voltage higher than the minimum is needed to be applied to power supply pin VIN1.

\*6 : For CMOS output products, high level output voltage which is generated when the transient response is released becomes input voltage of VIN.

## ■ OPERATIONAL EXPLANATION

- Timing Chart (Pull up voltage = Input voltage V<sub>IN1</sub>)



- #### ● Operational Notes (N-ch Open drain)

Timing Chart A (VIN1=voltages above release voltage, VIN2=sweep voltage)

Because a voltage higher than the minimum operating voltage is applied to the voltage input pin (VIN), ground voltage will be output at the output pin (VDET) during stage 3. (Stages 1, 2, 4, 5 are the same as in B below).

## Timing Chart B ( $V_{IN1}=V_{IN2}$ )

- ① When a voltage greater than the release voltage ( $V_{DR}$ ) is applied to the voltage input pin ( $V_{IN1}, V_{IN2}$ ), input voltage ( $V_{IN1}, V_{IN2}$ ) will gradually fall.

When a voltage greater than the detect voltage ( $V_{DF}$ ) is applied to the voltage input pin ( $V_{IN1}, V_{IN2}$ ), a state of high impedance will exist at the output pin ( $V_{DET1}, V_{DET2}$ ), so should the pin be pulled up, voltage will be equal to pull up voltage.

② When input voltage ( $V_{IN1}, V_{IN2}$ ) falls below detect voltage ( $V_{DF}$ ), output voltage ( $V_{DET1}, V_{DET2}$ ) will be equal to ground level ( $V_{SS}$ ).

③ Should input voltage ( $V_{IN1}, V_{IN2}$ ) fall below the minimum operational voltage ( $V_{MIN}$ ), output will become unstable. Should  $V_{IN2}$  fall below  $V_{MIN}$ , voltage at the output pin ( $V_{DET2}$ ) will be equal to ground level ( $V_{SS}$ ) if the power supply ( $V_{IN1}$ ) is within the operating voltage range.

\*In general the output pin is pulled up so output will be equal to pull up voltage.

④ Should input voltage ( $V_{IN1}, V_{IN2}$ ) rise above ground voltage ( $V_{SS}$ ), output voltage ( $V_{DET1}, V_{DET2}$ ) will equal ground level until the release voltage level ( $V_{DR}$ ) is reached.

⑤ When input voltage ( $V_{IN1}, V_{IN2}$ ) rises above release voltage, the output pin's ( $V_{DET1}, V_{DET2}$ ) voltage will be equal to the voltage dependent on pull up.

Note : The difference between release voltage ( $V_{DR}$ ) and detect voltage ( $V_{DF}$ ) is the Hysteresis Range ⑥.

## ■ NOTES ON USE

1. Please use this IC within the specified maximum absolute ratings.
2. Please ensure that input voltage  $V_{IN2}$  is less than  $V_{IN1} + 0.3V$ . (refer to N.B. 1 below)
3. With a resistor connected between the  $V_{IN1}$  pin and the input, oscillation is liable to occur as a result of through current at the time of release. (refer to N.B. 2 below)
4. With a resistor connected between the  $V_{IN1}$  pin and the input, detect and release voltage will rise as a result of the IC's supply current flowing through the  $V_{IN1}$  pin.
5. In order to stabilize the IC's operations, please ensure that the  $V_{IN1}$  pin's input frequency's rise and fall times are more than 5 msec/V.
6. Should the power supply voltage  $V_{IN1}$  exceed 6V, voltage detector 2's detect voltage ( $V_{DF2}$ ) and the release voltage ( $V_{DR2}$ ) will shift somewhat.
7. For CMOS output products, high level output voltage which is generated when the transient response is released becomes input voltage of  $V_{IN}$ .

### ●N.B.

1. Voltage detector 2's input voltage ( $V_{IN2}$ )

An input protect diode is connected from input detector 2's input ( $V_{IN2}$ ) to input detector 1's input. Therefore, should the voltage applied to  $V_{IN2}$  exceed  $V_{IN1}$ , current will flow through  $V_{IN1}$  via the diode. (refer to diagram1)

2. Oscillation as a result of through current

Since the XC612 series are CMOS ICs, through current will flow when the IC's internal circuit switching operates (during release and detect operations). Consequently, oscillation is liable to occur as a result of drops in voltage at the through current's resistor ( $R_{IN}$ ) during release voltage operations. (refer to diagram 2)

Since hysteresis exists during detect operations, oscillation is unlikely to occur.

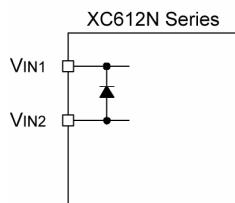


Diagram 1. Voltage detector 2's input voltage  $V_{IN2}$

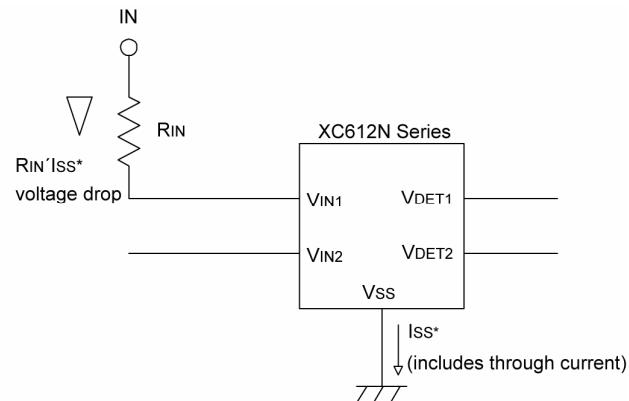
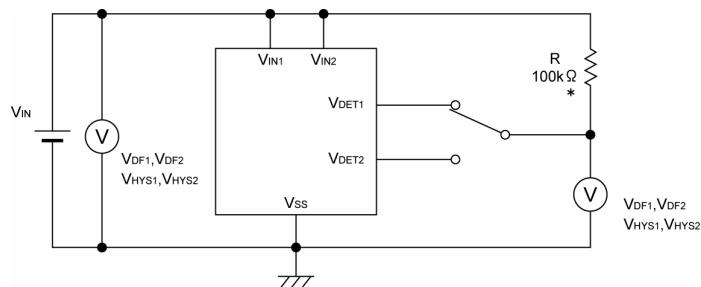


Diagram 2. Through current oscillation

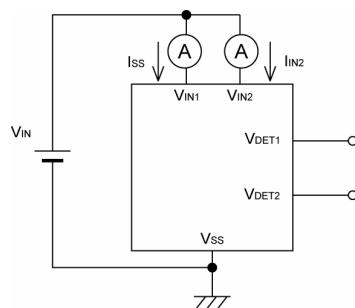
## TEST CIRCUITS

Circuit 1



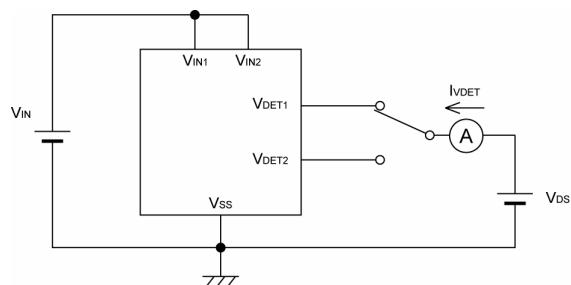
\* A resistor is not needed for CMOS output type.

Circuit 2

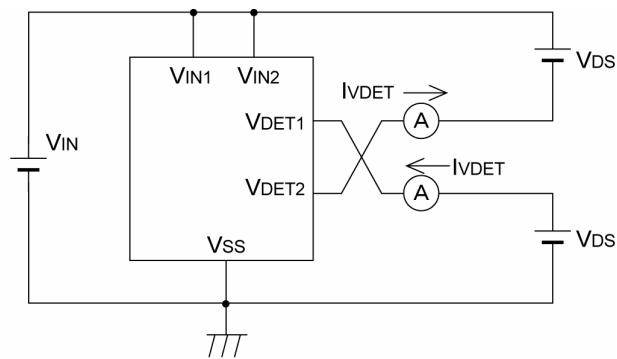


Circuit 3

XC612N Series



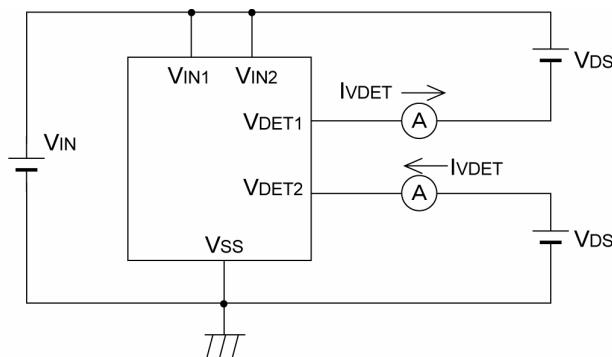
XC612D Series



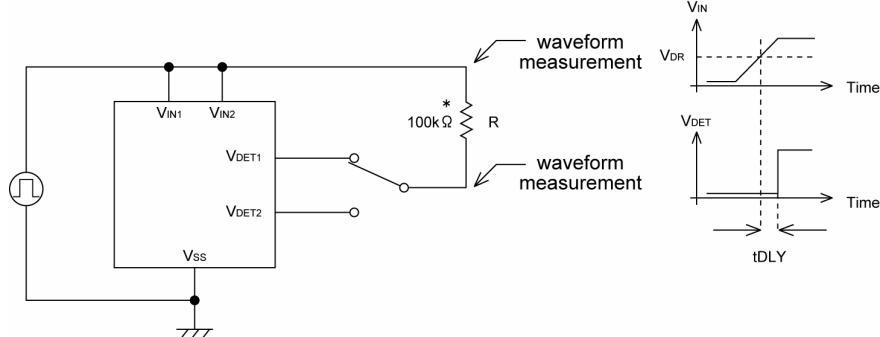
## ■ TEST CIRCUITS (Continued)

Circuit 3 (Continued)

XC612E Series

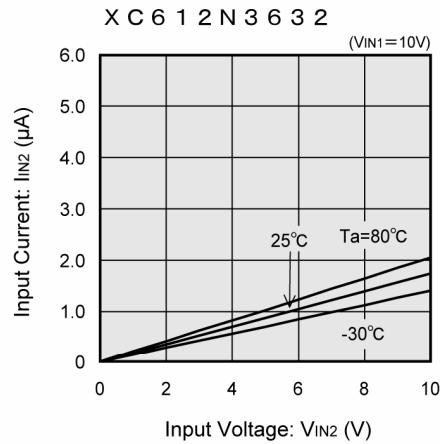
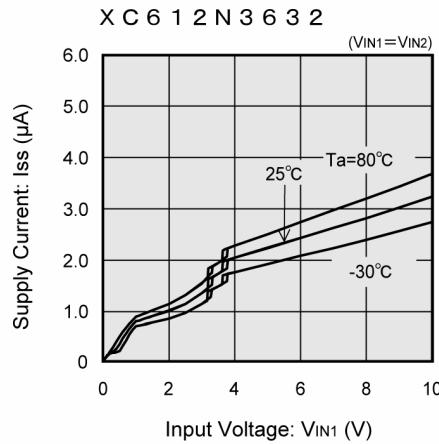


Circuit 4

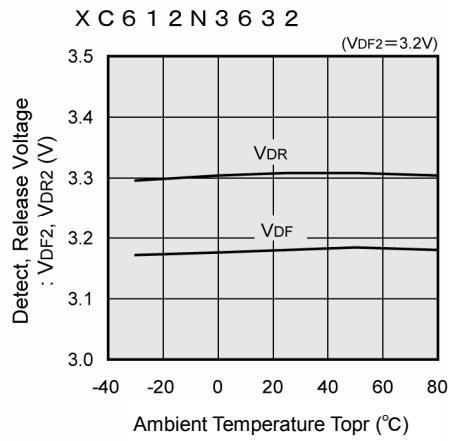
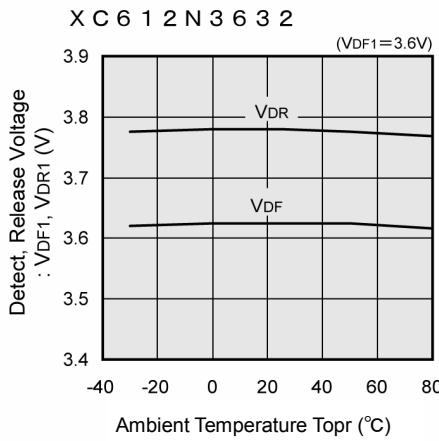


## ■ TYPICAL PERFORMANCE CHARACTERISTICS

(1) Supply Current vs. Input Voltage

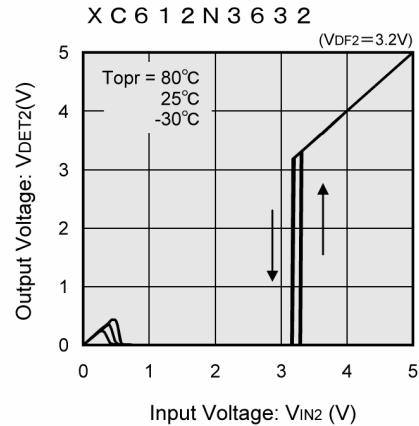
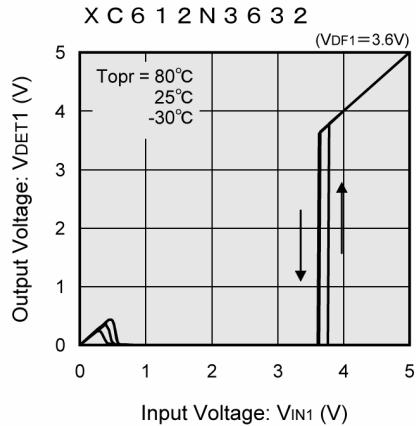


(2) Detect & Release Voltage vs. Ambient Temperature



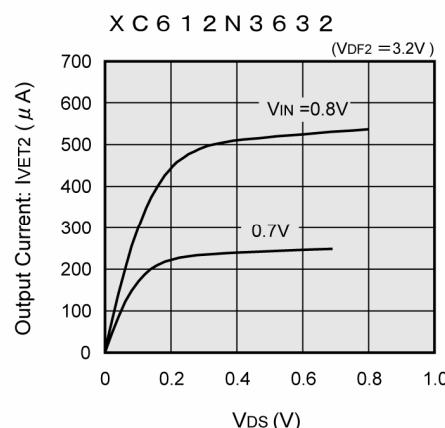
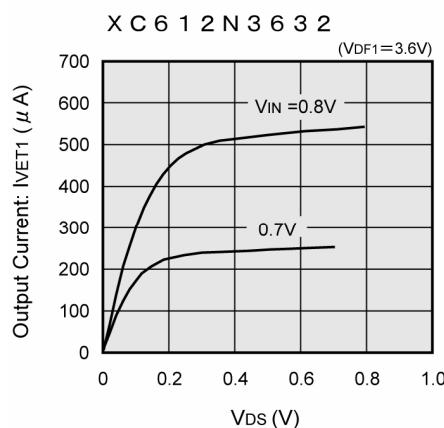
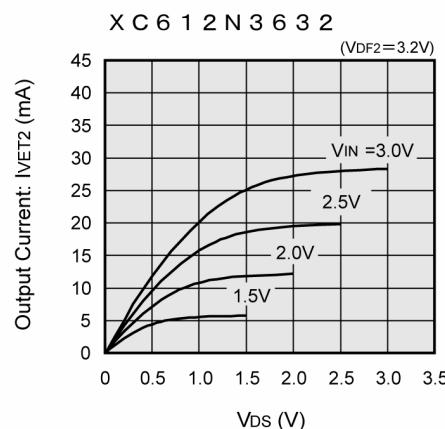
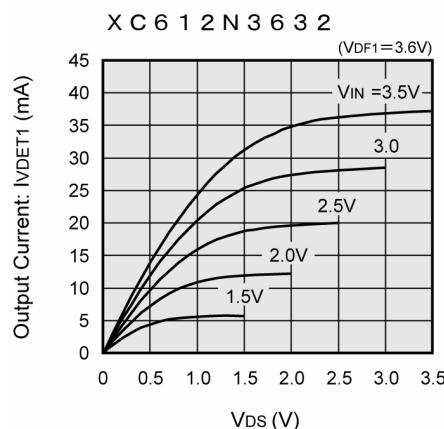
Note: Unless otherwise stated, pull up resistance = 100kΩ with N-ch open drain output type.

(3) Output Voltage vs. Input Voltage

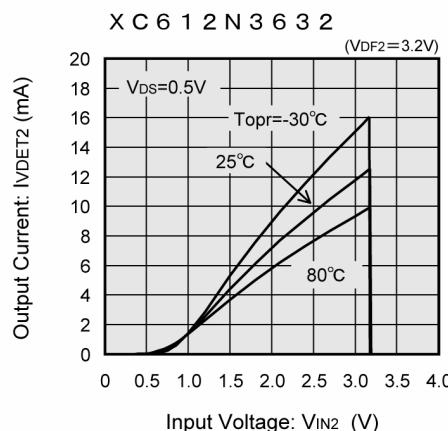
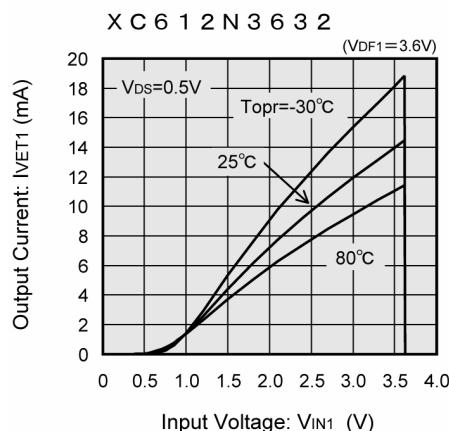


## ■TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

(4) N-ch Driver Output Current vs. V<sub>DS</sub>

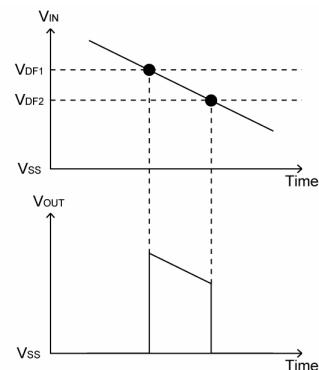
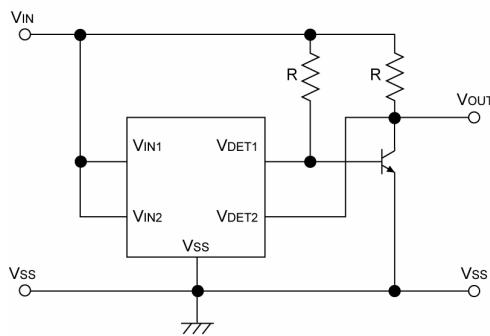


(5) N-ch Driver Output Current vs. Input Voltage

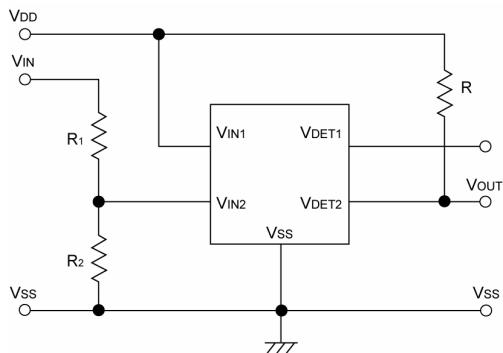


## ■ APPLICATION CIRCUITS EXAMPLE \*Example covers N-channel open drain product's circuits

- Window comparator circuit



- Detect voltages above respective established voltages circuit



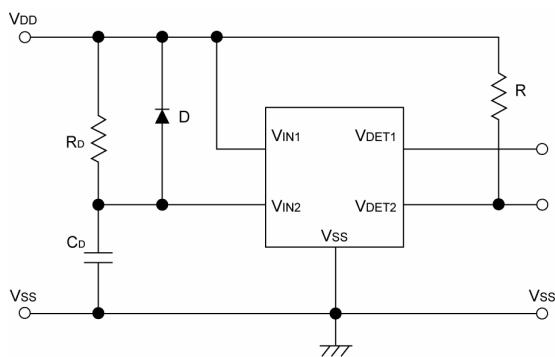
On resistors  $R_1$  and  $R_2$  equation (1) and (2)  
 $\text{Detect voltage} = \{(R_1 + R_2) \div R_2\} \times V_{DF2}$  (1)

N.B.  $V_{DF2}$  = detect voltage  $VD_2$

$Hysteresis (V_{HYS2}) = \{(R_1 + R_2) \div R_2\} \times V_{HYS2}$  (2)

Note: Please ensure that input voltage 2 ( $V_{IN2}$ ) is less than  $V_{IN1} + 0.3V$

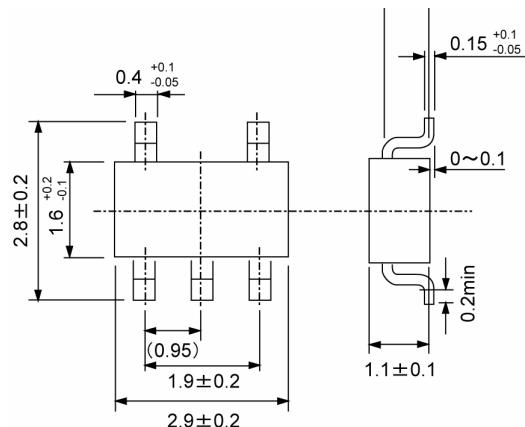
- Detect voltage circuit with delay built-in



Note: Delay operates at both times of release and detect operations.

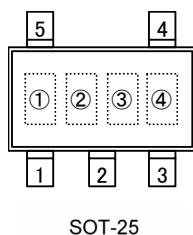
## ■ PACKAGING INFORMATION

● SOT-25



## ■ MARKING RULE

● SOT-25



①Represents output configuration

MARK	CONFIGURATION		PRODUCT SERIES
	VDET1	VDET2	
<u>N</u>	N-ch Open Drain	N-ch Open Drain	XC612NxxxxMx
<u>D</u>	N-ch Open Drain	CMOS	XC612DxxxxMx
<u>E</u>	CMOS	N-ch Open Drain	XC612ExxxxMx

②, ③Represents sequence number

④Represents production lot number  
0 to 9, A to Z repeated. (G, I, J, O, Q, W excepted.)

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